

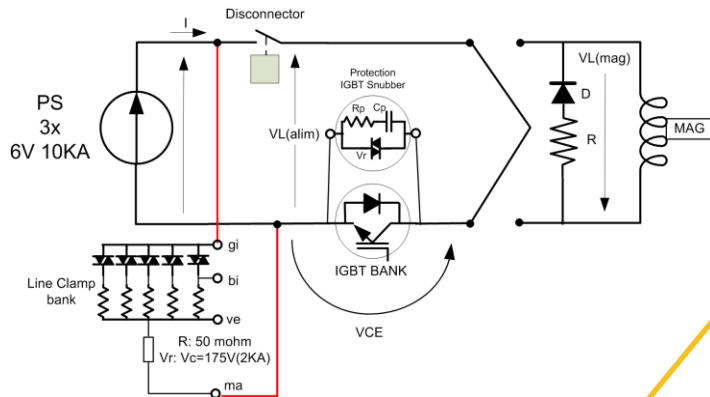


Status of LASA test facility



- Structural work to host the cryostat are in progress.
- The fast breaker has been tested and ready
- Cryogenics for variable temperature test
- QDS and acquisition/protection system

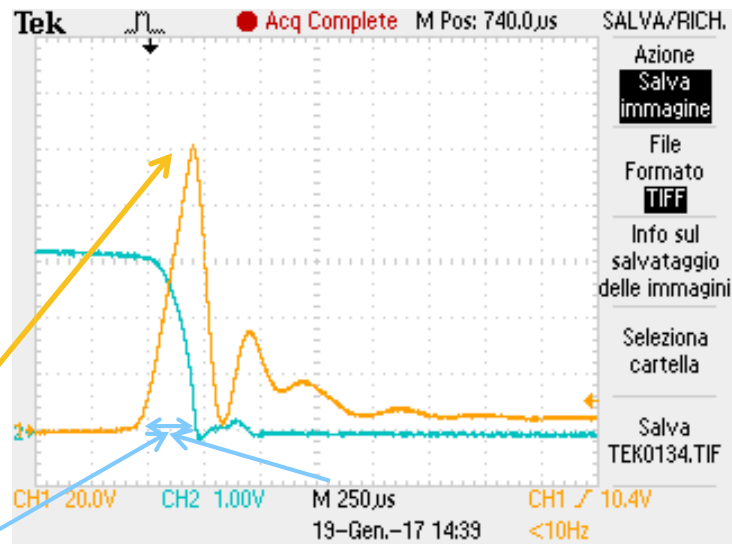
- IGBT (Insulated Gate Bipolar Transistor)
10kA-1kV



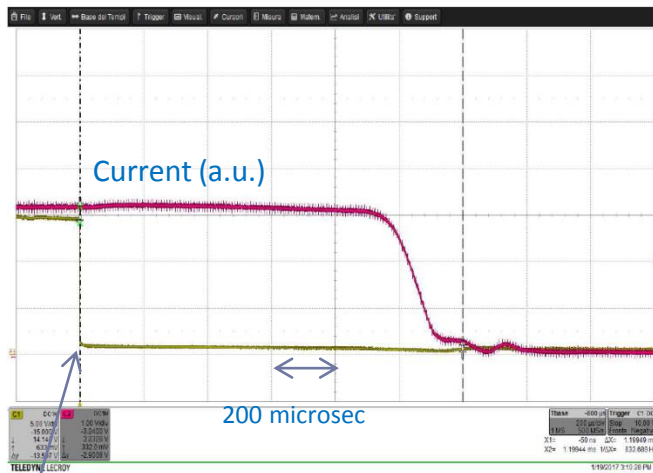
$I=10000A$

$VCE=500V$ (1/5 V divider)

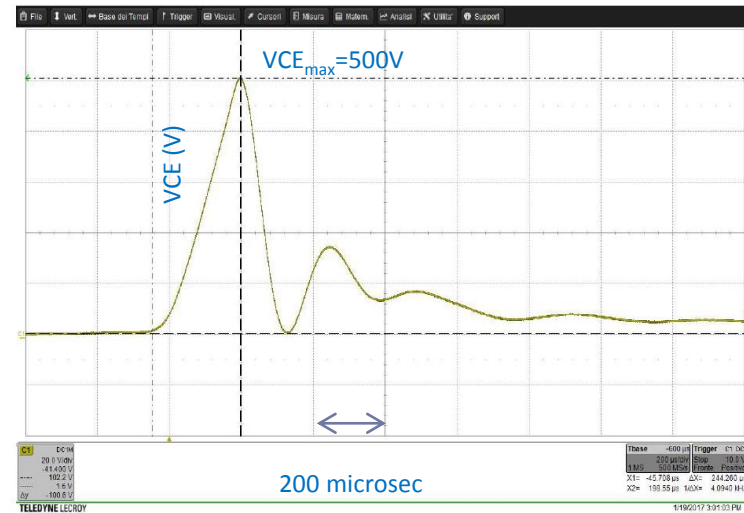
$T(off)=250$ microsec



Total execution time 1.2 ms



Voltage rise time 220 microsec





Cryogenics for variable temperature tests

- We are planning to change the (old) cryoplant
- We will install all the hardware to perform variable temperature



QDS and Data Acquisition

- Waiting